

Application/Control No.	Applicant(s)/Patent under Reexamination
10/710,778	32Qa
Examiner	Art Unit
Patricia Leith	1655

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
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	Subclass	Subclass Date			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE updated	7/31/2007	PL		
STN: indexed BIOSCIENCE cluster, approx. 76 databases (updated)	7/31/2007	PL		
Inventor name search updated EAST/PALM	7/31/2007	PL		